

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components, Assemblies, Related Materials and Processes

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Schedule of Scope to Certificate of Approval

Independent Testing Laboratory

IECQ Certificate No.: IECQ-L DEKRA 16.0002-02
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Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

Description test	Standard	Remarks
Consumer / Commercial / Industrial (JESD 47) and Automotive / Military accelerated environment reliability stress tests (Including: Pre-condition / MSL / Accelerated Temperature-Humidity test / Temperature-Humidity with bias test / Temperature Cycling test / Power and temperature cycling / Temperature storage test / Salt)	J-STD-020, JESD22-A101/A102/ A106/A107/A110/A113/A118/A119; IEC- 60068-2-1/2/3/14/ 38/52, MIL-STD-202/750/810/883,JESD JEP001; EIA-364-32, EIAJ ED-4701, AEC-Q200- 004; AEC-Q005/Q006,	Or customer specified test
Consumer/ Commercial / Industrial (JESD 47) and Automotive / Military accelerated lifetime simulation tests. (Including: Temperature, Bias, and Operating Life test / early life failure rate / Endurance and Data retention test / Short circuit / Miscellaneous test)	JESD22-A108/A117, MIL-STD-202/750/810/883, AEC-Q100-005/008/012, AEC-Q101-004/006,	Or customer specified test
IC package (Chip On Board)	AEC-Q005/Q006,	Or customer specified test

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